Regarding the change of names mentioned in the document, such as Mitsubishi Electric and Mitsubishi XX, to Renesas Technology Corp.

The semiconductor operations of Hitachi and Mitsubishi Electric were transferred to Renesas Technology Corporation on April 1st 2003. These operations include microcomputer, logic, analog and discrete devices, and memory chips other than DRAMs (flash memory, SRAMs etc.) Accordingly, although Mitsubishi Electric, Mitsubishi Electric Corporation, Mitsubishi Semiconductors, and other Mitsubishi brand names are mentioned in the document, these names have in fact all been changed to Renesas Technology Corp. Thank you for your understanding. Except for our corporate trademark, logo and corporate statement, no changes whatsoever have been made to the contents of the document, and these changes do not constitute any alteration to the contents of the document itself.

Note : Mitsubishi Electric will continue the business operations of high frequency & optical devices and power devices.

Renesas Technology Corp. Customer Support Dept. April 1, 2003



DESCRIPTION

The M5M5V108DFP,VP,KV are a 1048576-bit CMOS static RAM organized as 131072 word by 8-bit which are fabricated using highperformance triple-polysilicon and double metal CMOS technology. The use of thin film transistor (TFT) load cells and CMOS periphery result in a high density and low power static RAM.

They are low standby current and low operation current and ideal for the battery back-up application.

The M5M5V108DVP,KV are packaged in a 32-pin thin small outline package which is a high reliability and high density surface mount device(SMD).

FEATURES

Type name	Access		Power supply current			
	time (max)	Vcc	Active (1MHz) (max)	stand-by (max)		
M5M5V108DFP,VP,KV-70HI	70ns	2.7~3.6V	5mA	24µA		

- Directly TTL compatible : All inputs and outputs
- Data hold on +2V power supply
- Three-state outputs : OR tie capability
- OE prevents data contention in the I/O bus
- Common data I/O
- Package

M5M5V108DFP	32pin		
M5M5V108DVP,R\	/ 32pin	8 X 20 mm ²	TSOP
M5M5V108DKV,KF	R 32pin	8 X 13.4 mm	TSOP

APPLICATION

Small capacity memory units





FUNCTION

The operation mode of the M5M5V108D series are determined by a combination of the device control inputs \overline{S}_{1} , S_{2} , \overline{W} and \overline{OE} .

Each mode is summarized in the function table.

A write cycle is executed whenever the low level \overline{W} overlaps with the low level $\overline{S_1}$ and the high level S2. The address must be set up before the write cycle and must be stable during the entire cycle. The data is latched into a cell on the trailing edge of $\overline{W},\overline{S_1}$ or S2,whichever occurs first,requiring the set-up and hold time relative to these edge to be maintained. The output enable input \overline{OE} directly controls the output stage. Setting the \overline{OE} at a high level, the output stage is in a high-impedance state, and the data bus contention problem in the write cycle is eliminated.

A read cycle is executed by setting \overline{W} at a high level and \overline{OE} at a low level while \overline{S}_1 and S_2 are in an active state($\overline{S}_{1=L}, S_{2=H}$).

FUNCTION TABLE

ā	0	14/		Mada	DO	loo
S1	S2	W	OE	Mode	DQ	lcc
Х	L	Х	Х	Non selection High-impedanc		Stand-by
Н	Х	Х	Х	Non selection	High-impedance	Stand-by
L	Н	L	Х	Write	Din	Active
L	Н	Н	L	Read	Dout	Active
L	Н	Н	Н		High-impedance	Active

Note 1: "H" and "L" in this table mean VIH and VIL, respectively. 2: "X" in this table should be "H" or "L".

When setting \overline{S}_1 at a high level or S_2 at a low level, the chip are in a non-selectable mode in which both reading and writing are disabled. In this mode, the output stage is in a high- impedance state, allowing OR-tie with other chips and memory expansion by \overline{S}_1 and S_2 . The power supply current is reduced as low as the stand-by current which is specified as lcc3 or lcc4, and the memory data can be held at +2V power supply, enabling battery back-up operation during power failure or power-down operation in the non-selected mode.





7th.July.2000 Ver. 1.1 MITSUBISHI LSIs M5M5V108DFP,VP,KV -70HI 1048576-BIT(131072-WORD BY 8-BIT)CMOS STATIC RAM

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Unit
Vcc	Supply voltage		- 0.3*~4.6	V
Vi	Input voltage	With respect to GND	- 0.3*~Vcc + 0.3 (Max 4.6)	V
Vo	Output voltage		0~Vcc	V
Pd	Power dissipation	Ta=25°C	700	mW
Topr	Operating temperature		- 40~85	°C
Tstg	Storage temperature		- 65~150	°C

* –3.0V in case of AC (Pulse width 30ns)

DC ELECTRICAL CHARACTERISTICS (Ta=- 40~85°C, Vcc=2.7~3.6V, unless otherwise noted)

Symbol	Parameter	Test conditions				Limits		Unit
Symbol	Falameter				Min	Тур	Max	Unit
Vін	High-level input voltage				2.0		Vcc + 0.3	V
VIL	Low-level input voltage			-0.3*		0.6	V	
Voh1	High-level output voltage 1	Іон= – 0.5mA		2.4			V	
Voh2	High-level output voltage 2	Іон= – 0.05mA		Vcc - 0.5			V	
Vol	Low-level output voltage	IoL= 2mA				0.4	V	
li	Input current	VI=0~Vcc					±1	μA
lo	Output current in off-state	S1=VIH or S2=VIL or OE=VIH VI/0=0-VCC					±1	μA
laai		S1=VIL,S2=VIH,		70ns			35	
ICC1	Active supply current	other inputs=Vi⊢ or Vi∟		100ns			30	mA
ICC2	Active supply current	Output-open(duty 100%)		1MHz			5	
		1) S2 0.2V		~25°C			1.2	
Іссз	Stand by autrent	other inputs=0~Vcc		~40°C			3.6	
1003	Stand-by current	2) S1 Vcc-0.2V, S2 Vcc-0.2V	-HI	~70°C			12	μA
		other inputs=0~Vcc		~85°C			24	
ICC4	Stand-by current	S1=VIH or S2=VIL, other inputs=0~Vcc	1				0.33	mA

* -3.0V in case of AC (Pulse width 30ns)

CAPACITANCE (Ta=- 40~85°C, unless otherwise noted)

Currente e l	Parameter	Test and ditions		11.2		
Symbol		Test conditions	Min	Тур	Max	Unit
Сі	Input capacitance	VI=GND, VI=25mVrms, f=1MHz			8	pF
Со	Output capacitance	Vo=GND,Vo=25mVrms, f=1MHz			10	pF

Note 3: Direction for current flowing into an IC is positive (no mark).

4: Typical value is Vcc = 3V, Ta = 25°C



AC ELECTRICAL CHARACTERISTICS (Ta=- 40~85°C, unless otherwise noted)

(1) MEASUREMENT CONDITIONS

 $\label{eq:VCC} \begin{array}{c} V_{CC} & \cdots & 2.7 \text{-} 3.6 \text{V} \\ \text{Input pulse level} & \cdots & \text{VIH=} 2.2 \text{V}, \text{VIL=} 0.4 \text{V} \\ \text{Input rise and fall time} & \cdots & 5 \text{ns} \\ \text{Reference level} & \cdots & \text{VOH=} \text{VOL=} 1.5 \text{V} \\ \text{Output loads} & \cdots & \text{Fig.1, CL=} 30 \text{pF} \\ & \text{CL=} 5 \text{pF} \quad (\text{for ten,tdis}) \\ & \text{Transition is measured} \pm 500 \text{mV} \text{ from steady} \\ & \text{state voltage. (for ten,tdis)} \end{array}$



Fig.1 Output load

(2) READ CYCLE

	Parameter	Lim		
Symbol		-70	Unit	
		Min	Max	
tCR	Read cycle time	70		ns
ta(A)	Address access time		70	ns
ta(S1)	Chip select 1 access time		70	ns
ta(S2)	Chip select 2 access time		70	ns
ta(OE)	Output enable access time		35	ns
tdis(S1)	Output disable time after S1 high		25	ns
tdis(S2)	Output disable time after S2 low		25	ns
tdis(OE)	Output disable time after OE high		25	ns
ten(S1)	Output enable time after \overline{S}_1 low	10		ns
ten(S2)	Output enable time after S2 high	10		ns
ten(OE)	Output enable time after OE low	5		ns
t∨(A)	Data valid time after address	10		ns

(3) WRITE CYCLE

		Lin	nits		
Symbol	Parameter	-7	OHI	Unit	
		Min	Max		
tcw	Write cycle time	70		ns	
tw(W)	Write pulse width	55		ns	
t su(A)	Address setup time	0		ns	
tsu(A-WH)	Address setup time with respect to W	65		ns	
tsu(S1)	Chip select 1 setup time	65		ns	
tsu(S2)	Chip select 2 setup time	65		ns	
tsu(D)	Data setup time	30		ns	
t h(D)	Data hold time	0		ns	
trec(W)	Write recovery time	0		ns	
tdis(W)	Output disable time from \overline{W} low		25	ns	
tdis(OE)	Output disable time from OE high		25	ns	
ten(W)	Output enable time from \overline{W} high	5		ns	
ten(OE)	Output enable time from OE low	5		ns	



(4) TIMING DIAGRAMS Read cycle









Write cycle (S2 control mode)

- Note 5: Hatching indicates the state is "don't care".
 6: Writing is executed while S₂ high overlaps S₁ and W low.
 7: When the falling edge of W is simultaneously or prior to the falling edge of S₁
 - or rising edge of S2, the outputs are maintained in the high impedance state.
 - 8: Don't apply inverted phase signal externally when DQ pin is output mode.



POWER DOWN CHARACTERISTICS

(1) ELECTRICAL CHARACTERISTICS (Ta=- 40~85°C, unless otherwise noted)

Cumple al	Dementer	Tastassilitiass		Limits				
Symbol	Parameter	l est conditio	Test conditions			Тур	Max	Unit
VCC (PD)	Power down supply voltage				2			V
VI (S1)	Chip select input S1				2.0	Vcc(PD)		V
VI (S2) Chip select input S2		2.7V Vcc(PD)	.7V Vcc(PD)				0.6	V
	Chip select input S2	Vcc(PD)<2.7V	Vcc(PD)<2.7V				0.2	V
	Power down supply current	Vcc = 3V		~25°C			1	
		1) S2 0.2V, other inputs = 0~3V		~40°C			3	
ICC (PD)		2) S1 Vcc–0.2V, S2 Vcc–0.2V	-HI	~70°C			10	μA
		other inputs = $0 \sim 3V$		~85°C			20	

(2) TIMING REQUIREMENTS (Ta=- 40~85°C, unless otherwise noted)

Symbol	Parameter	Test see ditions		Linit		
		Test conditions	Min	Тур	Max	Unit
tsu (PD)	Power down set up time		0			ns
trec (PD)	Power down recovery time		5			ms

(3) POWER DOWN CHARACTERISTICS

\overline{S}_1 control mode



Note 9: On the power down mode by controlling $\overline{S_1}$, the input level of S₂ must be S₂ Vcc - 0.2V or S₂ 0.2V. The other pins(Address, I/O, \overline{WE} , \overline{OE}) can be in high impedance state.

S2 control mode Vcc S2 0.2V C.7V 2.7V 2.7V C.7V C.7V



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